
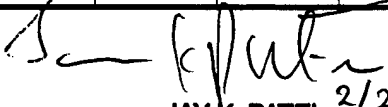
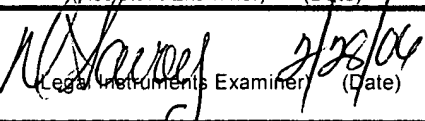


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/088,694	HAYATA, TOSHIHIRO	
	Examiner	Art Unit	
	Jacob Meek	2637	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
375		147			375	349			
INTERNATIONAL CLASSIFICATION									
H	0	4	B	1/69					
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				/					
				/					

Jacob Meek 2/24/06 (Assistant Examiner) (Date)	 JAY K. PATEL 2/28/06 SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date)	Total Claims Allowed: 8	
 Legal Instruments Examiner (Date)		O.G. Print Claim(s) 12	O.G. Print Fig. 2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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